

FIB (Quanta 3D)

집속이온빔

Quanta 3D is unique to other dual column instruments in that it is the first multi-mode SEM to harness the added power of the FIB. FIB technology is a proven technology that is now finding applications in research areas traditionally supported by SEM. The value of FIB is that it is complementary to SEM, delivering the ability to explore the third dimension of data below the surface of a sample, using various gases by environmental function and enabling a greater understanding of material characteristics and structures.

Model

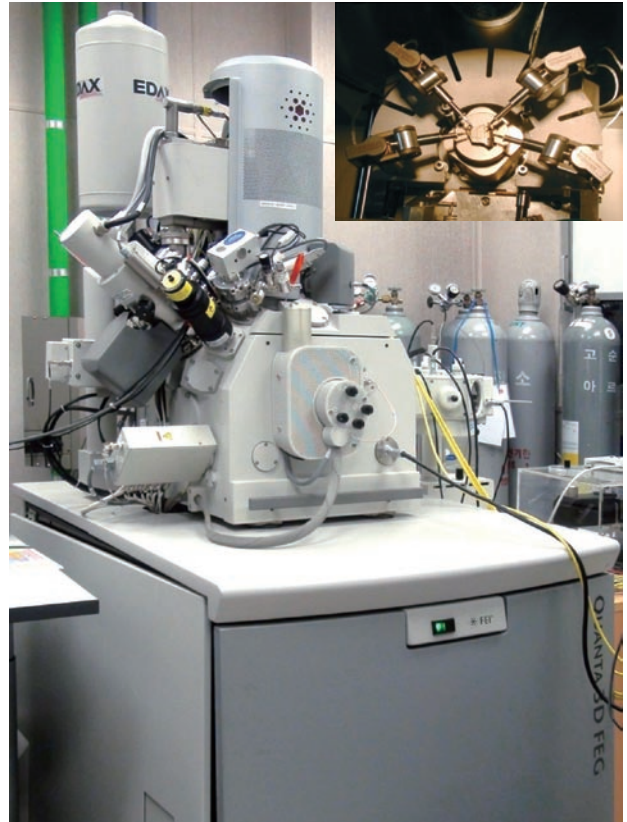
FEI (Quanta 3D FEG)

Specifications

- Accelerating voltage : 5 ~ 30 kV
- Image resolution : 1.2 nm (30 kV)
- Magnification : 30 ~ 1,280,000 X

Applications

- SE / BSE / Ion image
- STEM image
- EDS
- Charge neutralizer / Direct ion imaging
- Nano manipulator
- High vacuum
- Low vacuum (0.1~1 Torr)
- Cryo transfer system (Alto 2500)



Location L5115C Tel.02-958-6973

Failure analysis of semiconductor



In-situ I-V curve measurements of CNT (4-probe test)

